## 1. General description

PNP/PNP low  $V_{CEsat}$  Breakthrough In Small Signal (BISS) double transistor in a leadless medium power DFN2020D-6 (SOT1118D) Surface-Mounted Device (SMD) plastic package with visible and solderable side pads.

### 2. Features and benefits

- Very low collector-emitter saturation voltage V<sub>CEsat</sub>
- High collector current capability I<sub>C</sub> and I<sub>CM</sub>
- High collector current gain h<sub>FE</sub> at high I<sub>C</sub>
- Reduced Printed-Circuit Board (PCB) requirements
- Exposed heat sink for excellent thermal and electrical conductivity
- High energy efficiency due to less heat generation
- Suitable for Automatic Optical Inspection (AOI) of solder joints
- AEC-Q101 qualified

## 3. Applications

- Load switch
- Battery-driven devices
- Power management
- Charging circuits
- LED lighting
- Power switches (e.g. motors, fans)

#### 4. Quick reference data

Table 1. Quick reference data

Symbol	Parameter	Conditions		Min	Тур	Max	Unit
Per transistor							
V <sub>CEO</sub>	collector-emitter voltage	open base		-	-	-55	V
I <sub>C</sub>	collector current			-	-	-2	Α
I <sub>CM</sub>	peak collector current	single pulse; t <sub>p</sub> ≤ 1 ms		-	-	-3	Α
Per transistor							
V <sub>CEsat</sub>	collector-emitter saturation voltage	$I_{C}$ = -0.7 A; $I_{B}$ = -7 mA; pulsed; $t_{p} \le 300 \ \mu s; \ \delta \le 0.02 \ ; T_{amb}$ = 25 °C		-	-300	-420	mV





# 5. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	E1	emitter TR1	6 5 4	C1 B2 E2
2	B1	base TR1		
3	C2	collector TR2	7 8	(TR1) TR2)
4	E2	emitter TR2		
5	B2	base TR2	1 2 3	E1 B1 C2
6	C1	collector TR1	Transparent top view  DFN2020D-6 (SOT1118D)	sym138
7	C1	collector TR1	DEN2020D-0 (3011110D)	
8	C2	collector TR2		

# 6. Ordering information

Table 3. Ordering information

Type number	Package					
	Name	Description	Version			
PBSS5255PAPS	DFN2020D-6	DFN2020D-6: plastic, thermally enhanced ultra thin and small outline package; no leads; 6 terminals; body 2 x 2 x 0.65 mm	SOT1118D			

# 7. Marking

Table 4. Marking codes

Type number	Marking code
PBSS5255PAPS	3N

## 8. Limiting values

Table 5. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

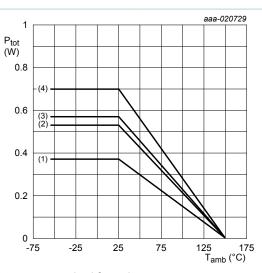
Symbol	Parameter	Conditions		Min	Max	Unit
Per transis	tor				'	
$V_{CBO}$	collector-base voltage	open emitter		-	-55	V
V <sub>CEO</sub>	collector-emitter voltage	open base		-	-55	V
V <sub>EBO</sub>	emitter-base voltage	open collector		-	-7	V
I <sub>C</sub>	collector current			-	-2	Α
I <sub>CM</sub>	peak collector current	single pulse; t <sub>p</sub> ≤ 1 ms		-	-3	Α
I <sub>B</sub>	base current			-	-0.3	Α
I <sub>BM</sub>	peak base current	single pulse; t <sub>p</sub> ≤ 1 ms		-	-1	Α
P <sub>tot</sub>	total power dissipation	T <sub>amb</sub> ≤ 25 °C	[1]	-	370	mW
			[2]	-	570	mW
			[3]	-	530	mW
			[4]	-	700	mW
Per device						
P <sub>tot</sub>	total power dissipation	T <sub>amb</sub> ≤ 25 °C	[1]	-	510	mW
			[2]	-	780	mW
			[3]	-	730	mW
			[4]	-	960	mW
T <sub>j</sub>	junction temperature			-	150	°C
T <sub>amb</sub>	ambient temperature			-55	150	°C
T <sub>stg</sub>	storage temperature			-65	150	°C

<sup>[1]</sup> Device mounted on an FR4 Printed-Circuit Board (PCB), single-sided copper, tin-plated and standard footprint.

<sup>[2]</sup> Device mounted on an FR4 PCB, single-sided copper, tin-plated, mounting pad for collector 1 cm<sup>2</sup>.

<sup>[3]</sup> Device mounted on an FR4 PCB, 4-layer copper, tin-plated and standard footprint.

<sup>[4]</sup> Device mounted on an FR4 PCB, 4-layer copper, tin-plated and mounting pad for collector 1 cm<sup>2</sup>.



- (1) FR4 PCB, single-sided copper, standard footprint
- (2) FR4 PCB, 4-layer copper, standard footprint
- (3) FR4 PCB, single-sided copper, 1 cm<sup>2</sup>
- (4) FR4 PCB, 4-layer copper, 1 cm<sup>2</sup>

Fig. 1. Power derating curves

### 9. Thermal characteristics

Table 6. Thermal characteristics

Symbol	Parameter	Conditions		Min	Тур	Max	Unit	
Per transistor	Per transistor							
R <sub>th(j-a)</sub>	thermal resistance		[1]	-	-	338	K/W	
from junction to ambient	1 · · · · ·		[2]	-	-	219	K/W	
	ambient		[3]	-	-	236	K/W	
			[4]	-	-	179	K/W	
Per device								
R <sub>th(j-a)</sub>	thermal resistance	in free air	[1]	-	-	246	K/W	
	from junction to ambient		[2]	-	-	161	K/W	
	ambient		[3]	-	-	172	K/W	
			[4]	-	-	131	K/W	

- [1] Device mounted on an FR4 PCB, single-sided copper, tin-plated and standard footprint.
- Device mounted on an FR4 PCB, single-sided copper, tin-plated, mounting pad for collector 1 cm<sup>2</sup>.
- [3] Device mounted on an FR4 PCB, 4-layer copper, tin-plated and standard footprint.
- [4] Device mounted on an FR4 PCB, 4-layer copper, tin-plated, mounting pad for collector 1 cm<sup>2</sup>.

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#### 55V, 2A PNP/PNP low VCEsat (BISS) double transistor

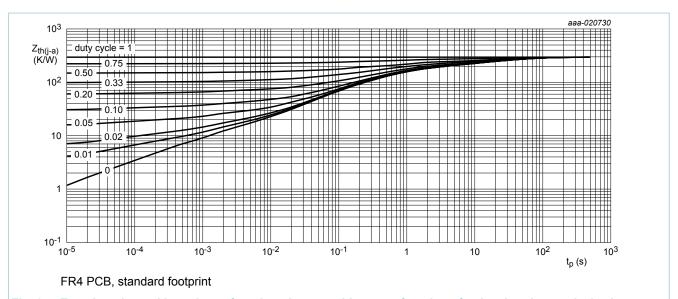


Fig. 2. Transient thermal impedance from junction to ambient as a function of pulse duration; typical values

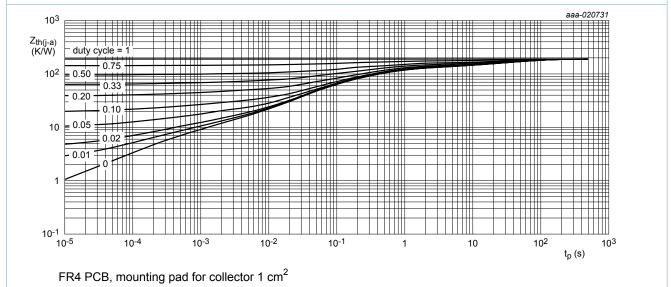


Fig. 3. Transient thermal impedance from junction to ambient as a function of pulse duration; typical values

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#### 55V, 2A PNP/PNP low VCEsat (BISS) double transistor

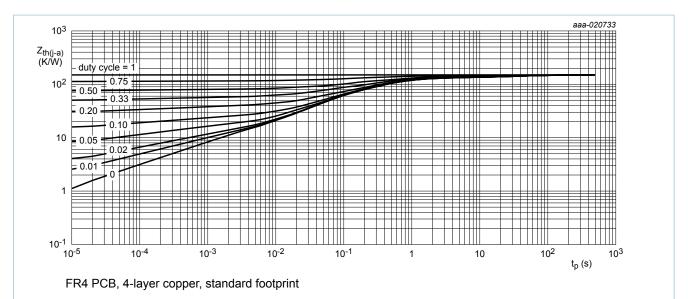
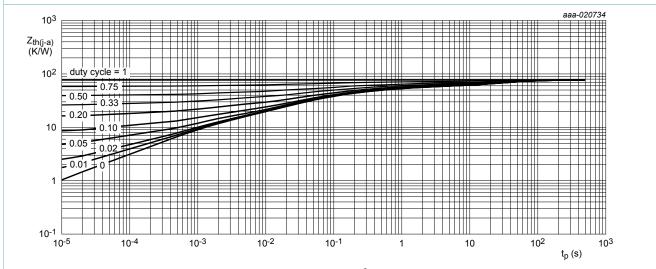


Fig. 4. Transient thermal impedance from junction to ambient as a function of pulse duration; typical values



FR4 PCB, 4-layer copper, mounting pad for collector 1 cm<sup>2</sup>

Fig. 5. Transient thermal impedance from junction to ambient as a function of pulse duration; typical values

## 10. Characteristics

Table 7. Characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Per transi	stor					
I <sub>CBO</sub>	collector-base cut-off	$V_{CB}$ = -44 V; $I_E$ = 0 A; $T_{amb}$ = 25 °C	-	-	-100	nA
current	current	$V_{CB} = -44 \text{ V}; I_E = 0 \text{ A}; T_j = 150 \text{ °C}$	-	-	-50	μΑ
I <sub>CES</sub>	collector-emitter cut-off current	$V_{CE} = -44 \text{ V}; V_{BE} = 0 \text{ V}; T_{amb} = 25 \text{ °C}$	-	-	-100	nA
ЕВО	emitter-base cut-off current	$V_{EB} = -5 \text{ V}; I_{C} = 0 \text{ A}; T_{amb} = 25 ^{\circ}\text{C}$	-	-	-100	nA
h <sub>FE</sub>	DC current gain	$V_{CE}$ = -2 V; $I_{C}$ = -100 mA; pulsed; $t_{p} \le 300 \ \mu s; \ \delta \le 0.02 \ ; T_{amb}$ = 25 °C	170	250	-	
		$V_{CE} = -2 \text{ V; } I_{C} = -500 \text{ mA; pulsed;}$ $t_{p} \le 300 \text{ µs; } \delta \le 0.02 \text{ ; } T_{amb} = 25 \text{ °C}$	140	200	-	
		$V_{CE}$ = -2 V; $I_{C}$ = -1 A; pulsed; $t_{p} \le 300 \ \mu s; \ \delta \le 0.02 \ ; T_{amb}$ = 25 °C	110	150	-	
		$V_{CE}$ = -2 V; $I_{C}$ = -2 A; pulsed; $t_{p} \le 300 \ \mu s; \ \delta \le 0.02 \ ; T_{amb}$ = 25 °C	50	75	-	
V <sub>CEsat</sub>	collector-emitter saturation voltage	$I_C$ = -0.5 A; $I_B$ = -50 mA; pulsed; $t_p \le 300 \ \mu s; \ \delta \le 0.02 \ ; T_{amb}$ = 25 °C	-	-80	-120	mV
		$I_{C}$ = -1 A; $I_{B}$ = -50 mA; pulsed; $t_{p} \le 300 \ \mu s; \ \delta \le 0.02 \ ; T_{amb} = 25 \ ^{\circ}C$	-	-170	-250	mV
		$I_{C}$ = -0.7 A; $I_{B}$ = -7 mA; pulsed; $t_{p} \le 300 \ \mu s; \ \delta \le 0.02 \ ; T_{amb}$ = 25 °C	-	-300	-420	mV
		$I_{C}$ = -2 A; $I_{B}$ = -200 mA; pulsed; $t_{p} \le 300 \ \mu s; \ \delta \le 0.02; \ T_{amb} = 25 \ ^{\circ}C$	-	-300	-450	mV
R <sub>CEsat</sub>	collector-emitter saturation resistance	$I_{C}$ = -1 A; $I_{B}$ = -50 mA; pulsed; $t_{p} \le 300 \ \mu s; \ \delta \le 0.02 \ ; T_{amb} = 25 \ ^{\circ}C$	-	-	250	mΩ
V <sub>BEsat</sub>	base-emitter saturation voltage	$I_{C}$ = -0.5 A; $I_{B}$ = -50 mA; pulsed; $t_{p} \le 300 \ \mu s; \ \delta \le 0.02 \ ; T_{amb}$ = 25 °C	-	-0.89	-1	V
		$I_{C}$ = -1 A; $I_{B}$ = -50 mA; pulsed; $t_{p} \le 300 \ \mu s; \ \delta \le 0.02; \ T_{amb} = 25 \ ^{\circ}C$	-	-0.93	-1	V
		$I_C$ = -2 A; $I_B$ = -200 mA; pulsed; $t_p \le 300 \text{ μs}; \delta \le 0.02; T_{amb} = 25 \text{ °C}$	-	-1.13	-1.25	V
$V_{BE}$	base-emitter voltage	$I_C$ = -0.5 A; $V_{CE}$ = -2 V; pulsed; $t_p \le 300 \ \mu s; \ \delta_{factor} \le 0.02; \ T_{amb}$ = 25 °C	-	-0.76	-0.9	V
d	delay time	I <sub>C</sub> = -1 A; I <sub>Bon</sub> = -50 mA; I <sub>Boff</sub> = 50 mA;	-	10	-	ns
r	rise time	T <sub>amb</sub> = 25 °C	-	80	-	ns
on	turn-on time		-	90	-	ns

NXP Semiconductors

## PBSS5255PAPS

### 55V, 2A PNP/PNP low VCEsat (BISS) double transistor

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
t <sub>s</sub>	storage time		-	195	-	ns
t <sub>f</sub>	fall time		-	75	-	ns
t <sub>off</sub>	turn-off time		-	270	-	ns
f <sub>T</sub>	transition frequency	V <sub>CE</sub> = -10 V; I <sub>C</sub> = -500 mA; f = 100 MHz; T <sub>amb</sub> = 25 °C	-	100	-	MHz
C <sub>c</sub>	collector capacitance	V <sub>CB</sub> = -10 V; I <sub>E</sub> = 0 A; i <sub>e</sub> = 0 A; f = 1 MHz; T <sub>amb</sub> = 25 °C	-	16	-	pF

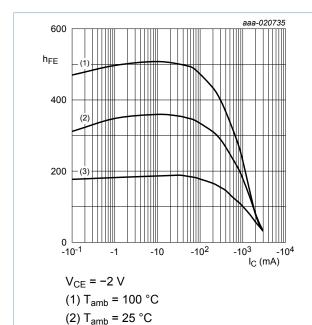


Fig. 6. DC current gain as a function of collector current; typical values

(3)  $T_{amb} = -55 \, ^{\circ}C$ 

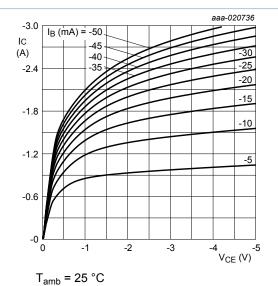
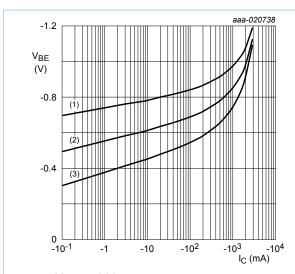


Fig. 7. Collector current as a function of collectoremitter voltage; typical values

**Product data sheet** 



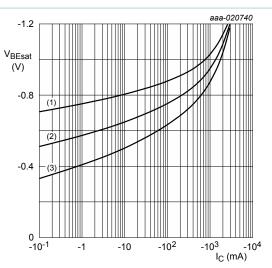
$$V_{CE} = -2 V$$

(1) 
$$T_{amb} = -55 \, ^{\circ}C$$

(2) 
$$T_{amb} = 25 \, ^{\circ}C$$

(3) 
$$T_{amb} = 100 \, ^{\circ}C$$

Fig. 8. Base-emitter voltage as a function of collector current; typical values



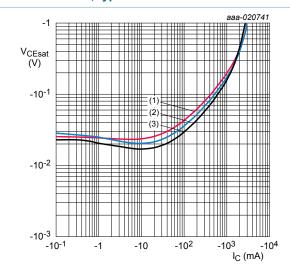
$$I_{\rm C}/I_{\rm B} = 20$$

(1) 
$$T_{amb} = -55 \, ^{\circ}C$$

(2) 
$$T_{amb} = 25 \, ^{\circ}C$$

(3) 
$$T_{amb} = 100 \, ^{\circ}C$$

Fig. 9. Base-emitter saturation voltage as a function of collector current; typical values



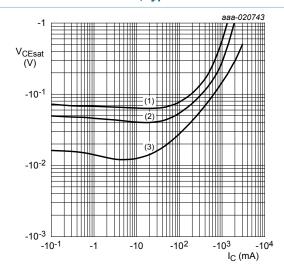
$$I_{\rm C}/I_{\rm B} = 20$$

(1) 
$$T_{amb} = 100 \, ^{\circ}C$$

(2) 
$$T_{amb}$$
 = 25 °C

$$(3) T_{amb} = -55 °C$$

Fig. 10. Collector-emitter saturation voltage as a function of collector current; typical values

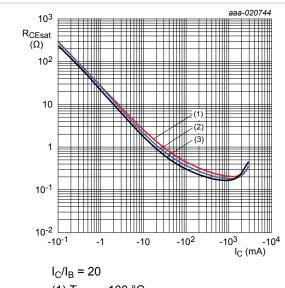


(1) 
$$I_C/I_B = 100$$

(2) 
$$I_C/I_B = 50$$

(3) 
$$I_C/I_B = 10$$

Fig. 11. Collector-emitter saturation voltage as a function of collector current; typical values

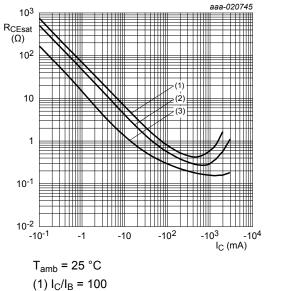


(1) 
$$T_{amb} = 100 \, ^{\circ}C$$

(2) 
$$T_{amb}$$
 = 25 °C

(3) 
$$T_{amb} = -55 \, ^{\circ}C$$

Fig. 12. Collector-emitter saturation resistance as a function of collector current; typical values



$$(1) I_C/I_B = 10$$

(2) 
$$I_C/I_B = 50$$

(3) 
$$I_C/I_B = 10$$

Fig. 13. Collector-emitter saturation resistance as a function of collector current; typical values

### 11. Test information

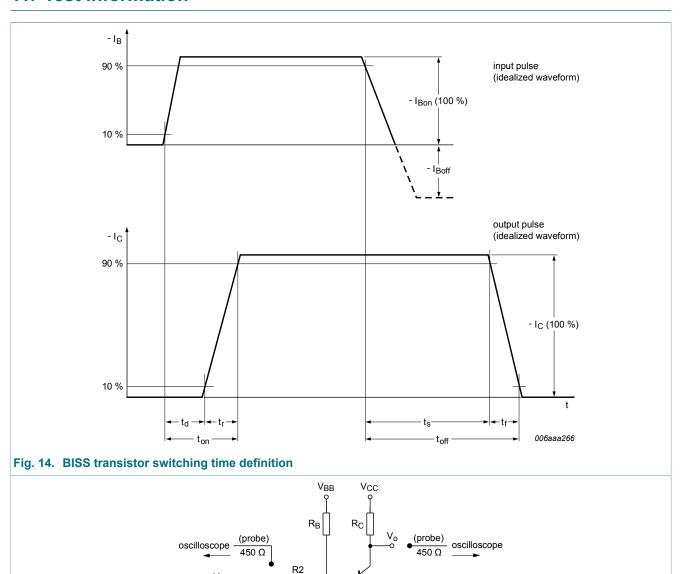


Fig. 15. Test circuit for switching times

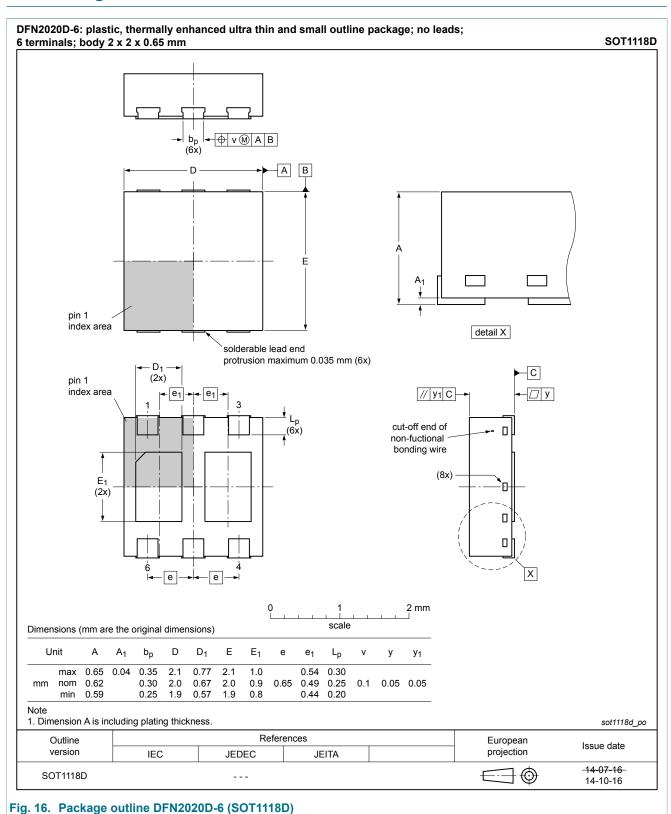
### 11.1 Quality information

This product has been qualified in accordance with the Automotive Electronics Council (AEC) standard *Q101 - Stress test qualification for discrete semiconductors*, and is suitable for use in automotive applications.

mgd624

DUT

## 12. Package outline



PBSS5255PAPS

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## 13. Soldering

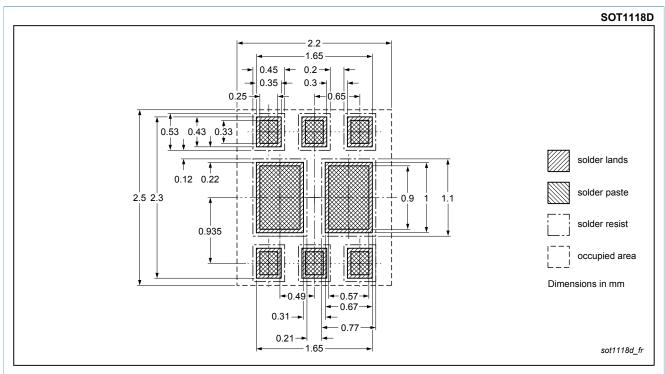


Fig. 17. Reflow soldering footprint for DFN2020D-6 (SOT1118D)

# 14. Revision history

#### Table 8. Revision history

Data sheet ID	Release date	Data sheet status	Change notice	Supersedes
PBSS5255PAPS v.1	20151211	Product data sheet	-	-

## 15. Legal information

#### 15.1 Data sheet status

Document status [1][2]	Product status [3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
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#### 55V, 2A PNP/PNP low VCEsat (BISS) double transistor

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